

Form PTO-149 <div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> OFFICE FEB 08 2002 PATENT & TRADEMARK OFFICE </div>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. JM32810-CIP		SERIAL NO. 10,046,330		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Wuwen Yi et al		PRIORITY GROUP 2818		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
PD ↑	AA	6,214,177 B1	04/01	Runkle	-	-		
	AB	5,294,321	03/94	Satou et al	-	-		
	AC	5,612,571	03/97	Satou et al	-	-		
	AD	5,464,520	11/95	Kano et al	-	-		
	AE	5,618,397	04/97	Kano et al	-	-		
	AF	6,033,537	03/00	Suguro	-	-		
	AG	5,955,685	09/99	Na	-	-		
	AH	5,415,829	05/95	Ohhashi et al	-	-		
	AI	5,409,517	04/95	Satou et al	-	-		
	AJ	4,619,697	10/86	Hijikata et al	-	-		
PD ↓	AK	5,320,729	06/94	Narizuka et al	-	-		
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
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*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								